

Defects in Cl and Na doped CdTe monograin powders

Altosaar, Mare; Kuk, Peeter-Enn; Raudoja, Jaan; Mellikov, Enn E-MRS Spring Meeting : Strasbourg, 1999 : abstracts 1999 / p. O-32 <https://www.sciencedirect.com/science/article/abs/pii/S0040609099008135>

Impurity interaction with point defects in the Si-SiO₂ structures and its influence on the interface properties

Kropman, Daniel; Mellikov, Enn; Kärner, T.; Ugaste, Ülo; Laas, Tõnu; Heinmaa, I.; Medvid, A. Materials science and engineering : B 2006 / p. 222-226 : ill <https://www.sciencedirect.com/science/article/pii/S0921510706004375>

Influence of point defects on physical qualities of semiconductors

Altosaar, Mare; Buschmann, Felix; Erm, Ants; Krustok, Jüri; Kuk, Peeter-Enn; Lõo, A.; Mädasson, Jaan; Tomson, A. Journal of materials and product. technology 1991

Interaction between point defects in the Si-Si=2 system

Kropman, Daniel; Kärner, T.; Samoson, Ago; Heinmaa, I.; Mellikov, Enn Nuclear instruments & methods in physics research. Section B 2002 / p. 78-82 <https://www.sciencedirect.com/science/article/pii/S0168583X0100862X>

Interaction between point defects in the Si-SiO₂ system during the process of its formation

Kropman, Daniel; Kärner, T.; Samoson, Ago; Heidmaa, I.; Ugaste, Ülo; Mellikov, Enn Defect and Diffusion Forum 2001 / p. 1737-1744 <https://www.sciencedirect.com/science/article/abs/pii/S0168583X0100862X>

Interaction of point defects with impurities in the Si-SiO₂ system and its influence on the interface properties

Kropman, Daniel; Mellikov, Enn; Kärner, Tiit; Heinmaa, Ivo; Laas, Tõnu; Londos, Charalampos; Misiuk, Andrzej Solid state phenomena 2011 / p. 263-266 <https://www.sciencedirect.com/science/article/pii/S0040609009014564>

Interaction of point defects with impurities in the Si-SiO₂ system and its influence on the interface properties

Kropman, Daniel; Kärner, Tiit; Dolgov, Sergei; Heinmaa, Ivo; Laas, Tõnu; Londos, Charalampos Physica status solidi (c) 2011 / p. 694-696 : ill <https://www.sciencedirect.com/science/article/pii/S0040609009014564>

Interaktsioon punktdefektide ja lisandite vahel süsteemis Si-SiO₂ ja nende mõju piirpinna omadustele : [ettekande sisukokkuvõte]

Kropman, Daniel; Kärner, T.; Heinmaa, I. Eesti Füüsika Seltsi aastaraamat 2008 2009 / lk. 119-120

Point defects interaction with extended defects and impurities and its influence on the Si-SiO₂ system properties

Kropman, Daniel; Arbu, Uno; Kärner, T.; Ugaste, Ülo; Mellikov, Enn; Kauk, Marit; Heinmaa, I.; Samoson, Ago; Medvid, A. Gettering and defect engineering in semiconductor technology. XI 2005 / p. 333-338 : ill https://www.researchgate.net/publication/243760197_Point_Defects_Interaction_with_Extended_Defects_and_Impurities_and_Its_Influence_on_the_Si-SiO_2_System_Properties

Point defects interaction with extended defects in the Si-SiO₂ system [Electronic resource]

Kropman, Daniel; Kärner, T.; Abru, Uno; Ugaste, Ülo; Mellikov, Enn Proceedings IVC-16 : Venice, 2004 2004 / p. SS1-TuP394 [CD-ROM] https://www.researchgate.net/publication/243760197_Point_Defects_Interaction_with_Extended_Defects_and_Impurities_and_Its_Influence_on_the_Si-SiO_2_System_Properties

Solid electrolytes for fluoride ion batteries : ionic conductivity in polycrystalline tysonite-type fluorides

Rongeat, Carine; Reddy, M. Anji; Witter, Raiker; Fichtner, Maximilian ACS applied materials and interfaces ACS applied materials & interfaces 2014 / p. 2103-2110 : ill <https://doi.org/10.1021/am4052188> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Точечные дефекты и процессы их образования в сульфидах кадмия и цинка : автореферат ... кандидата химических наук (02.00.04)

Mädasson, Jaan vt.ka Raudoja, Jaan 1987 https://www.ester.ee/record=b1521477*est